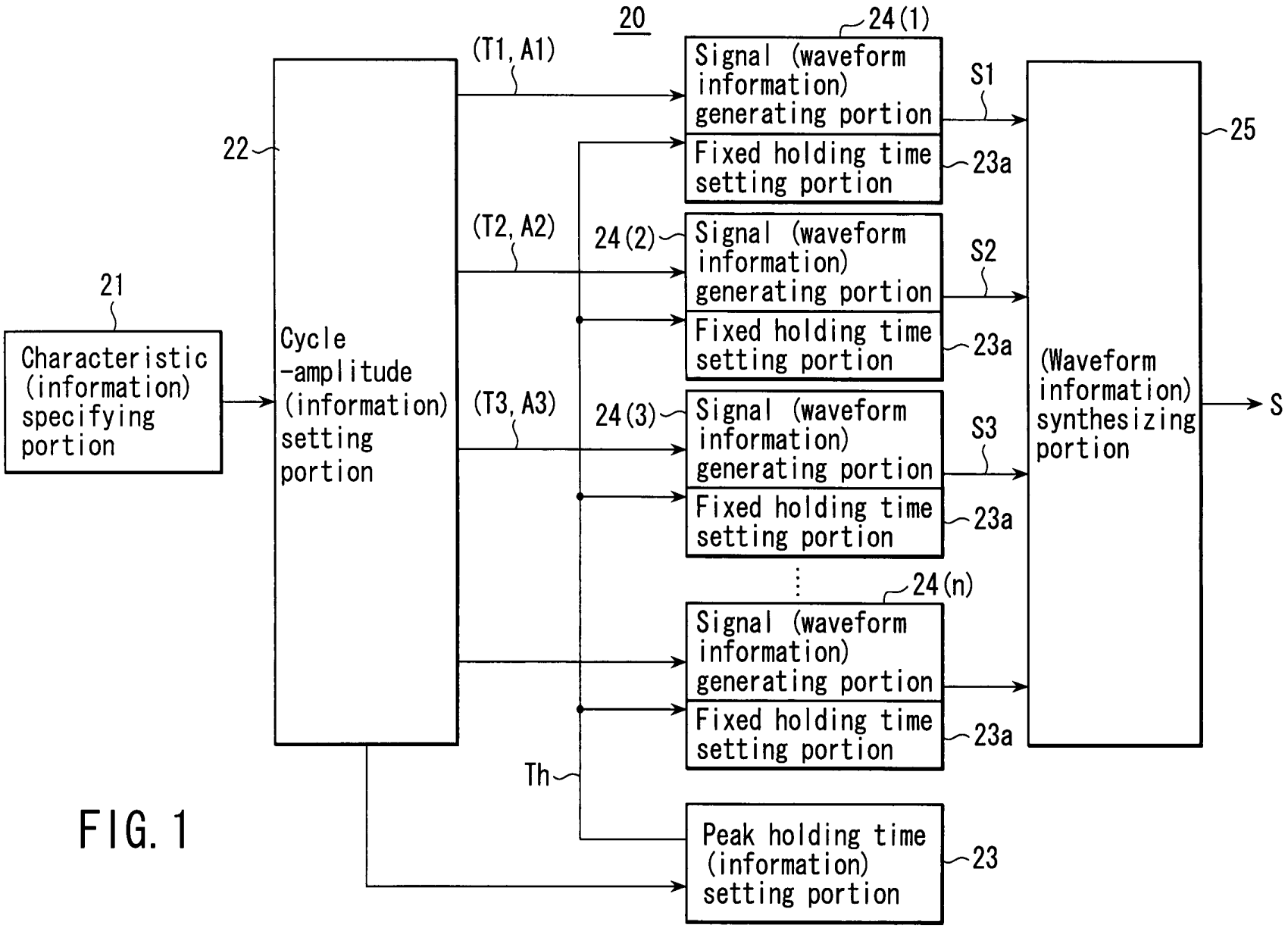
20
24(1)
Signal (waveform information) generating portion
Fixed holding time setting portion
23a
S1
25
(T1, A1)
22
(T2, A2)
24(2)
Signal (waveform information) generating portion
Fixed holding time setting portion
23a
S2
21
Characteristic (information) specifying portion
Cycle -amplitude (information) setting portion
(T3, A3)
24(3)
Signal (waveform information) generating portion
Fixed holding time setting portion
23a
S3
(Waveform information) synthesizing portion
S
24(n)
Signal (waveform information) generating portion
Fixed holding time setting portion
23a
Th
Peak holding time (information) setting portion
23

FIG. 1

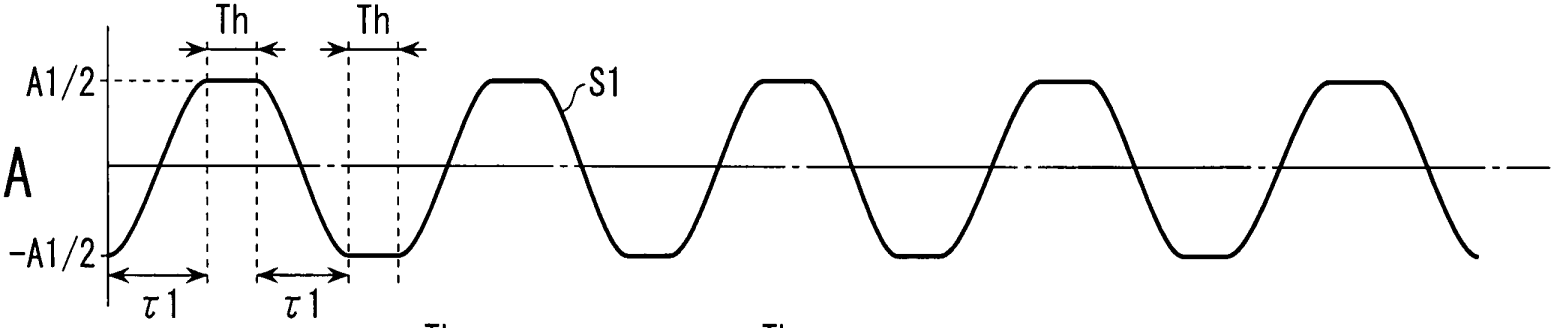

FIG. 2A

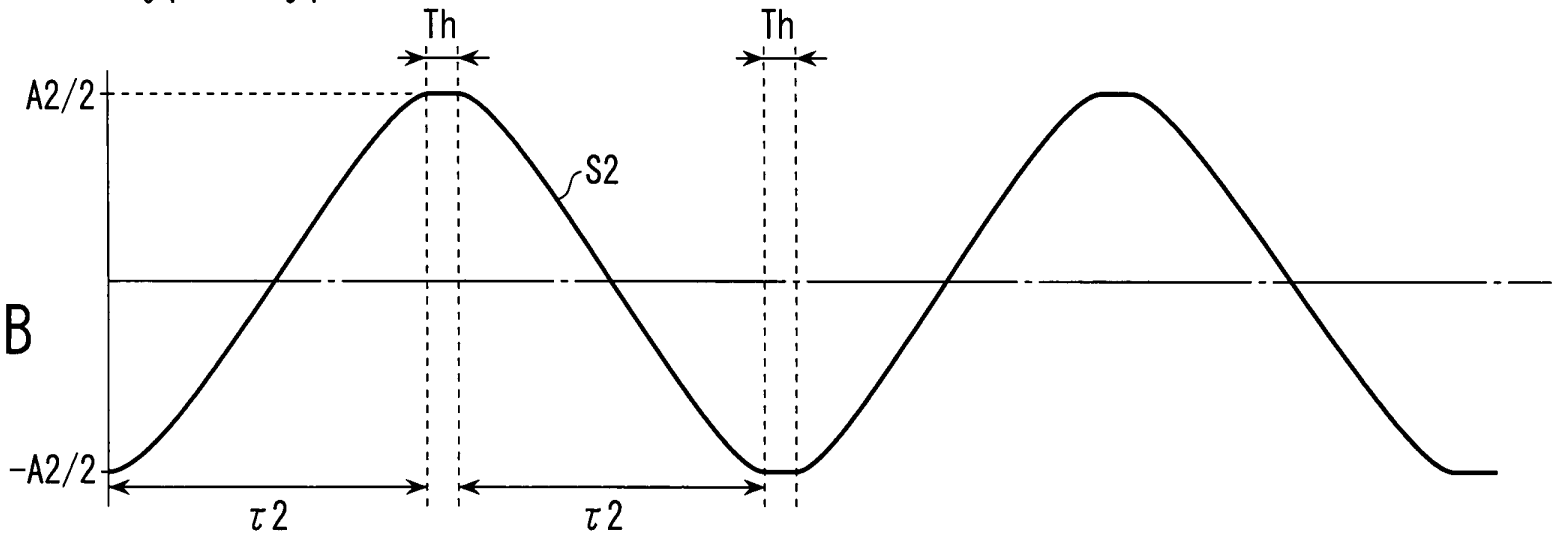

FIG. 2B

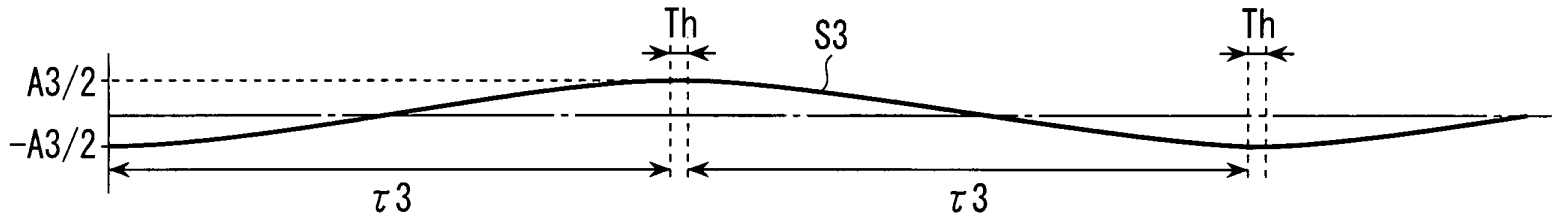

FIG. 2C

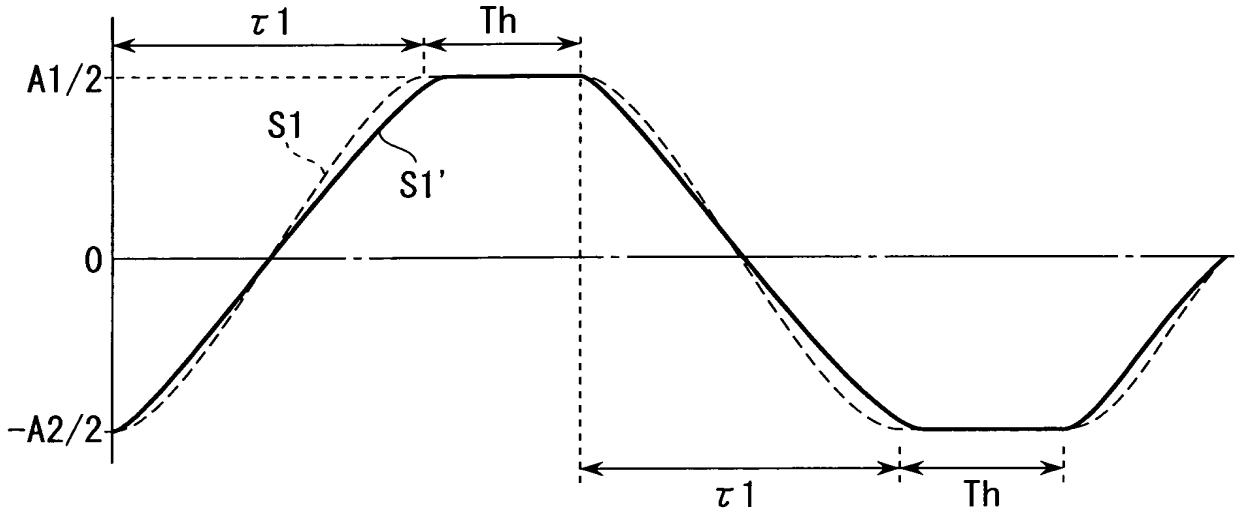
τ1
Th
A1/2
S1
S1'
0
-A2/2
τ1
Th

FIG. 3A

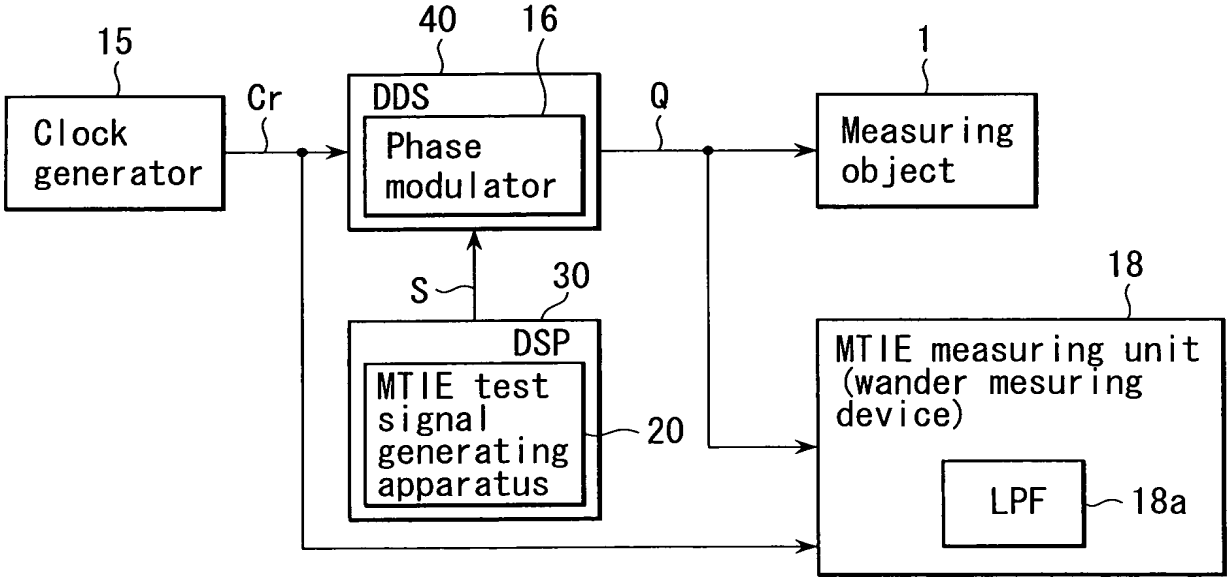
15
Clock generator
Cr
40
16
DDS
Phase modulator
Q
1
Measuring object
S
30
DSP
MTIE test signal generating apparatus
20
18
MTIE measuring unit (wander mesuring device)
LPF
18a

FIG. 3B

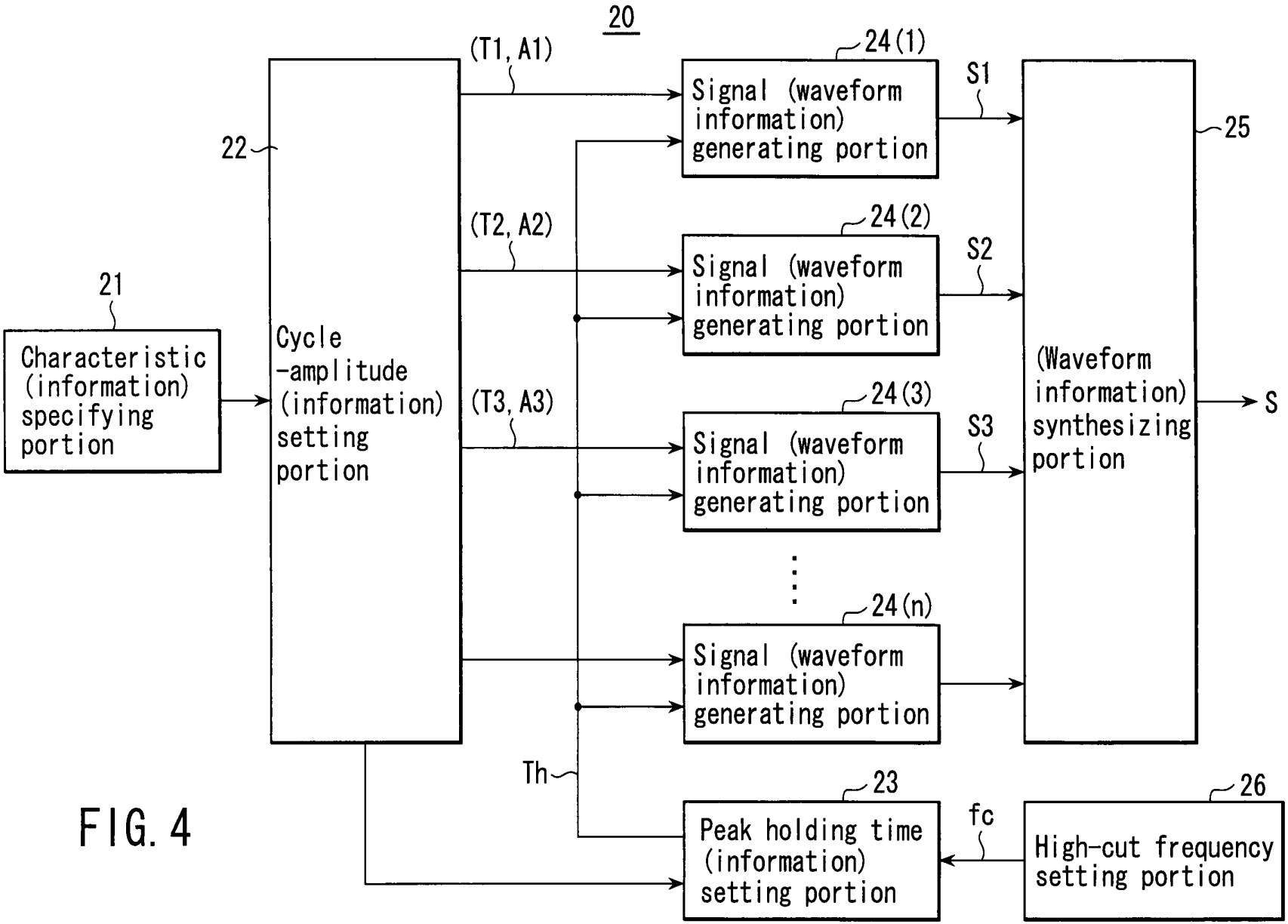
20
21
Characteristic (information) specifying portion
22
Cycle -amplitude (information) setting portion
(T1, A1)
(T2, A2)
(T3, A3)
Th
24(1)
Signal (waveform information) generating portion
24(2)
Signal (waveform information) generating portion
24(3)
Signal (waveform information) generating portion
24(n)
Signal (waveform information) generating portion
S1
S2
S3
25
(Waveform information) synthesizing portion
S
23
Peak holding time (information) setting portion
fc
26
High-cut frequency setting portion

FIG. 4

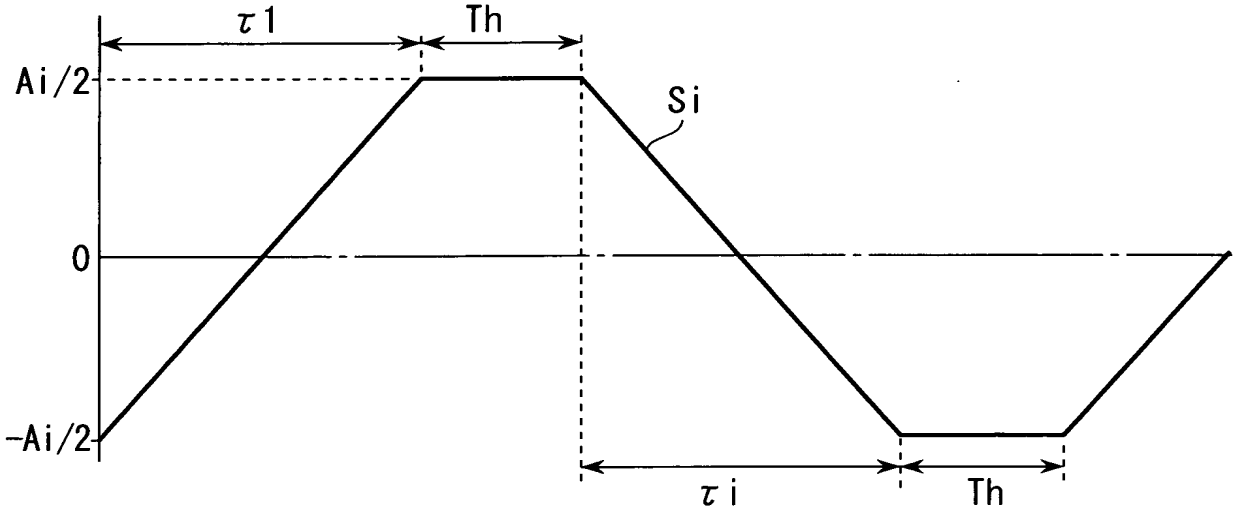

FIG. 5

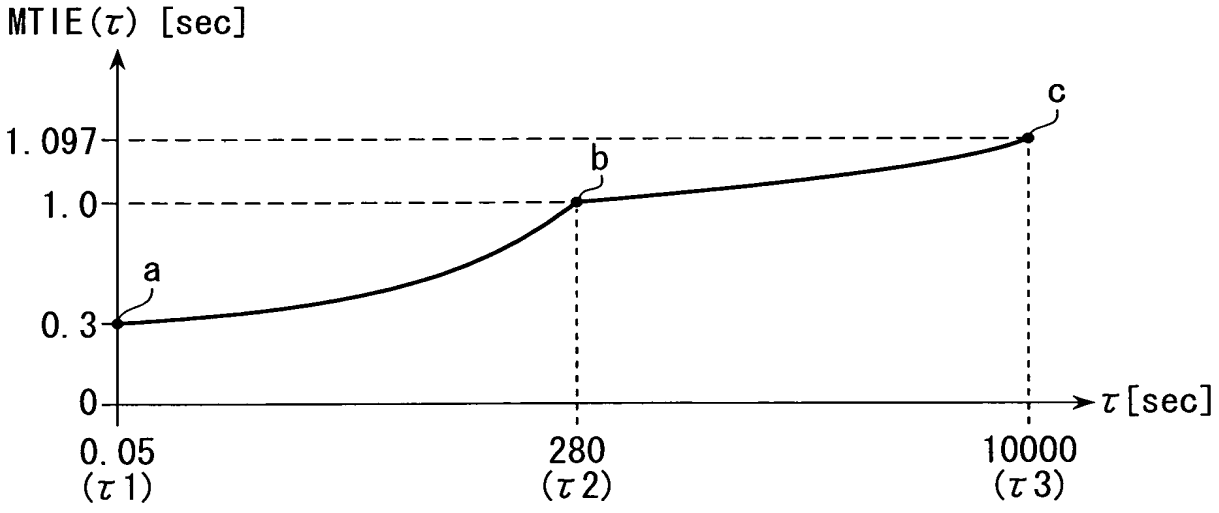

FIG. 6 (PRIOR ART)

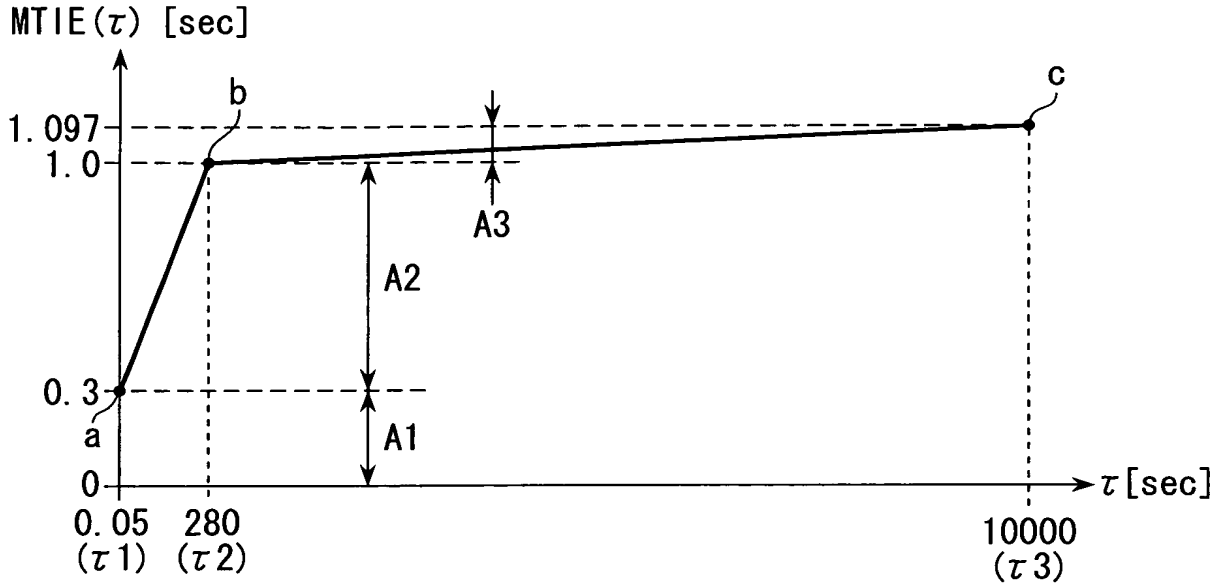

FIG. 7 (PRIOR ART)

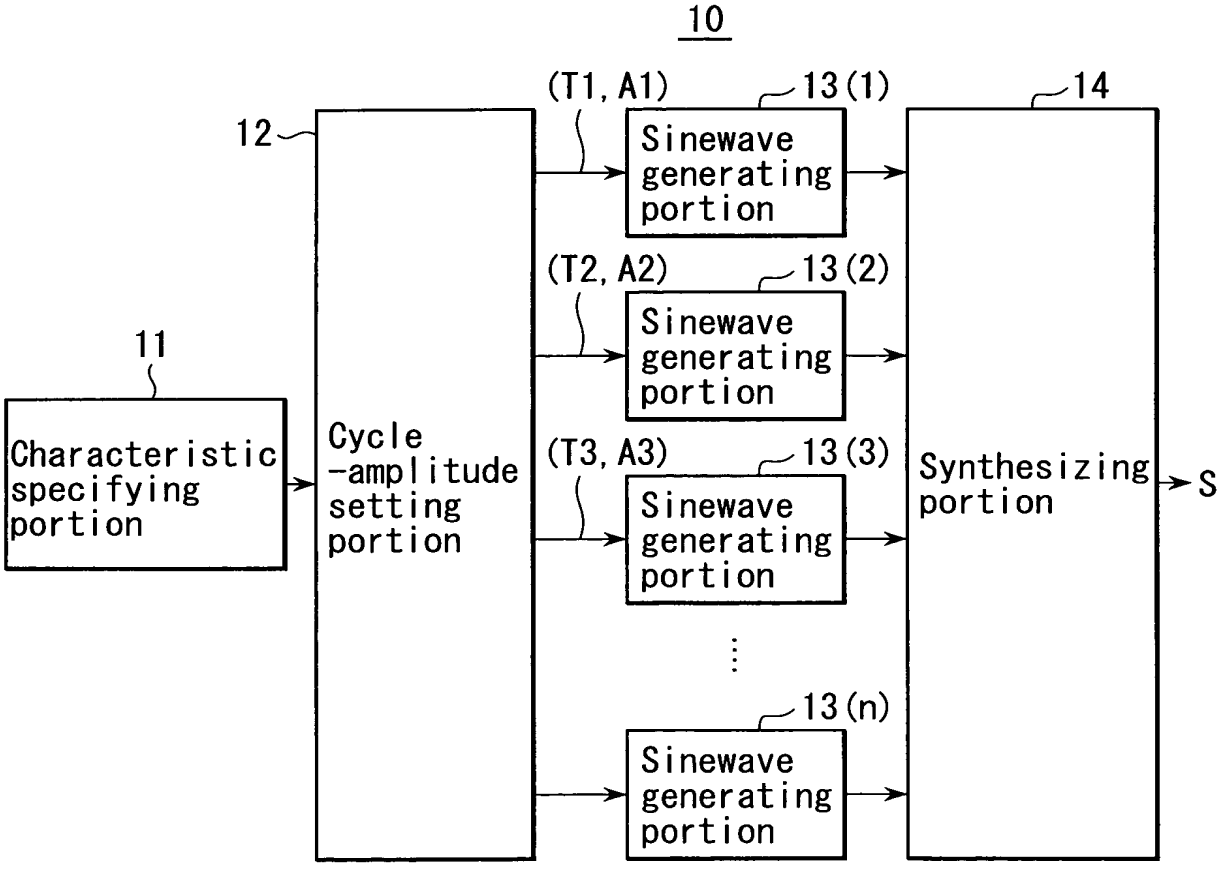

FIG. 8 (PRIOR ART)

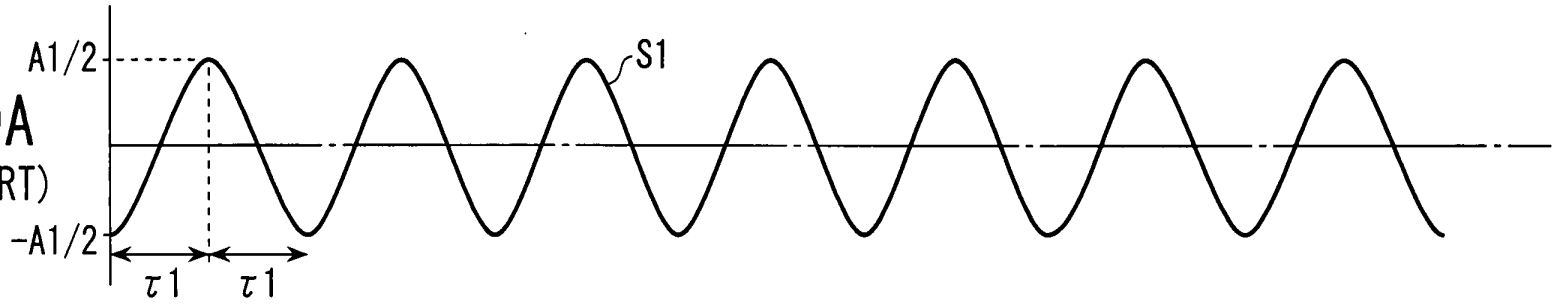

FIG. 9A
(PRIOR ART)

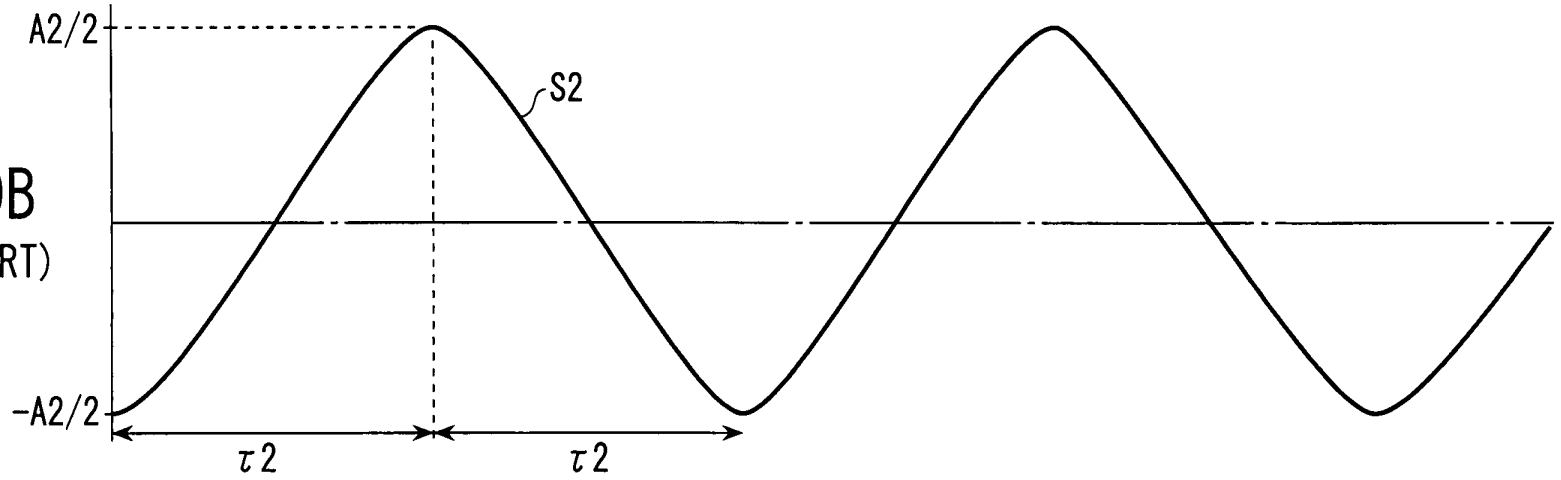

FIG. 9B
(PRIOR ART)

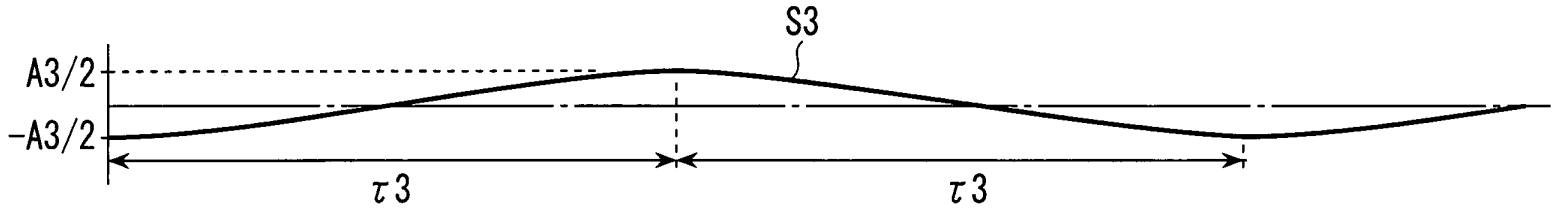

FIG. 9C (PRIOR ART)

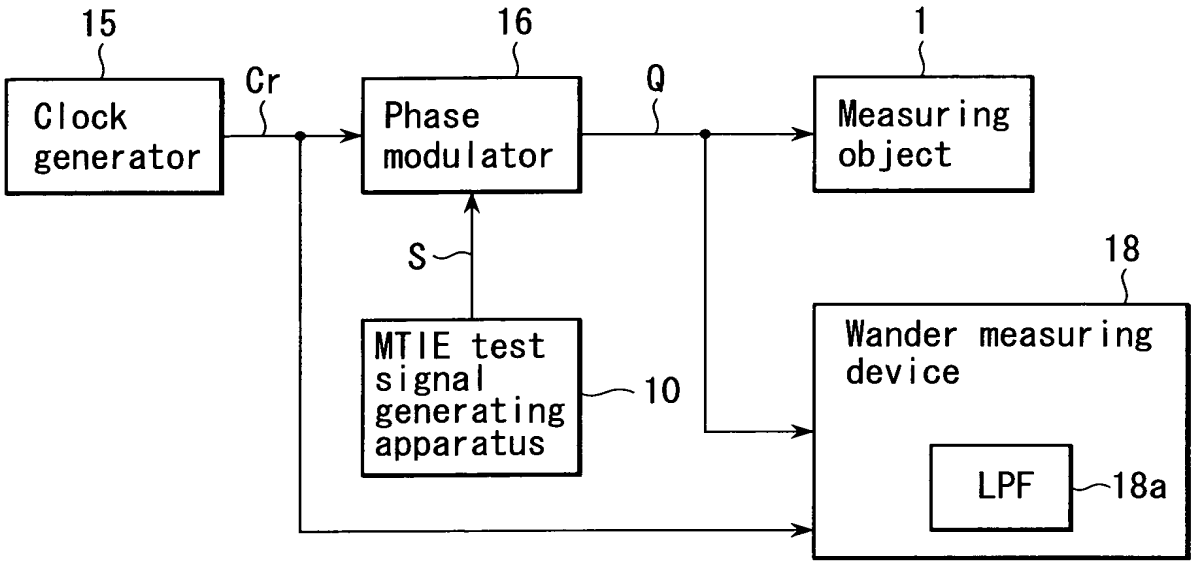

FIG. 10 (PRIOR ART)

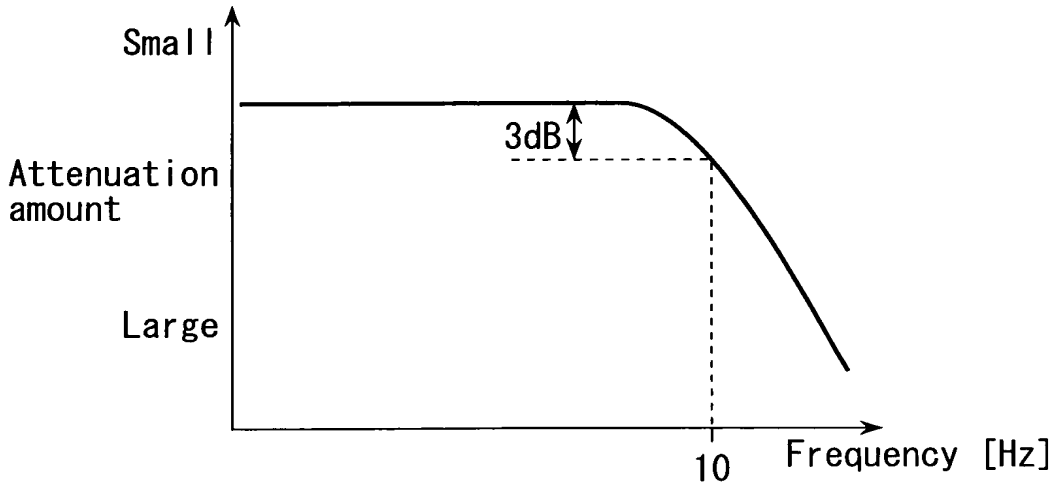

FIG. 11 (PRIOR ART)